## A Current-mode peak detector circuit

V. Riewruja., A. Linthong., A. Kaewpoonsuk., R. Guntapong and S. Supaph

Faculty of Engineering, King Mongkut's Institute of Technology Ladkrabang, Ladkrabang, Bangkok 10520, Thailand.

(Tel: 66-2-739-1362; Fax:66-2-326-9989; E-mail: vanchai@cs.eng.kmitl.ac.th)

## **Abstract**

In this article, a current mode peak detector circuit is presented. The simple circuit configuration comprises four MOS transistors and one external capacitor. The realization method is suitable for fabrication using CMOS technology and all transistors are operated in their saturation region. The proposed circuit exhibits a very low drop rate and provides high accuracy, high-speed and wide dynamic range. The proposed circuit has very low power dissipation and operates using a single 2.5V supply. Simulation results confirmed the characteristic of the proposed circuit are also included.

## 1. Introduction

A peak detector is a useful circuit building block used in electronic systems, analog measurement and instrumentation. For example, it can be used in AC voltmeter to measure non-sinusoidal waveform [1], [2], an automatic voltage regulation loop of an uninterruptible power supply [3], a nuclear pulse spectroscopy [4], an automatic voltage gain control in radio receiver [5] and a floppy and hard disk drives [6]. Classical approach that can usually be employed to realize peak detector is through the use of diode and capacitor. The limitation of this approach is the detecting signal amplitude must greater than the diode "on" voltage to avoid an inaccuracy. Usually, the application of peak detector requires the signal amplitude in the order of millivolts or microampere. The use of diode in the feedback loop of an operational amplifier (op-amp) has been used to improve an accuracy of the classical approach. However, in practice it is not economical for integrated circuit design, particularly for the case of opamp type, since each op-amp requires a substantial chip area in itself. Recently, the high frequency peak detector realizable in monolithic form is introduced [5]. The realization technique is based on bipolar technology and provides a differential output to eliminate the output offset voltage. In CMOS technology, the further references on the realization of a peak detector can be found in [6] - [8]. The MOS precision current peak detector is proposed in [6]. The advantage of this approach is a simple circuit configuration and a low voltage operation. However, the

use of MOS transistors operate in class B and MOS diode are effected the speed of the peak detector. The purpose of this article is to propose a CMOS circuit technique for the realization of a current peak detector. The realization method can result in fully integrated peak detector. The resulting performances of the circuit have high accuracy, high speed and wide dynamic range.

## 2. Circuit description

The proposed current-mode CMOS peak detector is shown in figure 1. Assuming that the transistors M<sub>1</sub> and M<sub>2</sub> are well matched and all transistors operate in their saturation regions. The operation of the circuit can be explained as follows. The transistors M<sub>1</sub> - M<sub>3</sub> form as a unity gain current mirror. The transistors M<sub>3</sub> and M<sub>4</sub> function as a current follower to provided a charge current to the capacitor C<sub>1</sub> and a path of the negative current I<sub>in</sub>, respectively. If the positive input signal current I<sub>in</sub> > 0, the current lin flows through the input of the current mirror M<sub>1</sub> - M<sub>3</sub> that cause the voltage at node A to increase and the gate-source voltage of the transistor M4 to decrease effecting the transistor M<sub>4</sub> to cutoff. The gate-source voltage of the transistor M<sub>1</sub>, V<sub>C</sub>, is risen and held by the capacitor C<sub>1</sub> with the charge current from the transistor M<sub>3</sub>. The voltage  $V_C$  can be written as

$$V_C = \sqrt{\frac{2I_{in}}{\beta_1}} + V_T \tag{1}$$

where  $\beta_1$  and  $V_T$  are the transconductance parameter  $(K'_PW/L)$  and the threshold voltage, respectively, of the transistor  $M_1$ . The gate-source of the transistor  $M_2$  is connected to the capacitor  $C_1$  then the drain current of the transistor  $M_2$ ,  $I_{out}$ , can be stated as

$$I_{out} = I_{d1} = K_P \frac{W}{2L} (V_C - V_T)^2$$
 (2)

where  $I_{d1}$  is the drain current of the transistor  $M_1$ . When the capacitor voltage rises to the steady voltage  $V_C$  that causes the transistor  $M_3$  to cutoff. The voltage  $V_C$  still forces the transistors  $M_1$  and  $M_2$  to operate equal drain current. If the